II. AMENDMENTS TO THE SPECIFICATION:

Please replace the title of the invention with the following title:

-- SYSTEM AND METHOD FOR GENERATING A SET OF TEST PATTERNS FOR AN OPTICAL PROXIMITY CORRECTION ALGORITHM --

Please replace the Abstract of the application with the following Abstract:

-- A system and method of synthesizing layout patterns to test an optical proximity correction algorithm. The method comprises the steps of: embodying Walsh patterns in a set of Walsh pattern matrices; processing groups of matrices from the set of Walsh pattern matrices to form a set of test matrices; mapping the set of test matrices to a test pattern set.--